

Search Notes

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Examiner

Le Nguyen

Applicant(s)/Patent under
Reexamination

GEIER ET AL.

Art Unit

2174

SEARCHED

Class	Subclass	Date	Examiner
715	769	11/22/2005	LVN

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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